Inventor: Antonio Marroig Martinez
Title: RAM DIAGNOSTIC READ CIRCUIT PROVIDING EXTERNAL INTEGRATED CIRCUIT RAM FAILURE DIAGNOSIS AND METHOD
Attorney: Pamela L. Kee (408) 553-3059
PDNO: 10030373-1

OIPE IAP65 AUG 18 2006 PATENT & TRADEMARK OFFICE

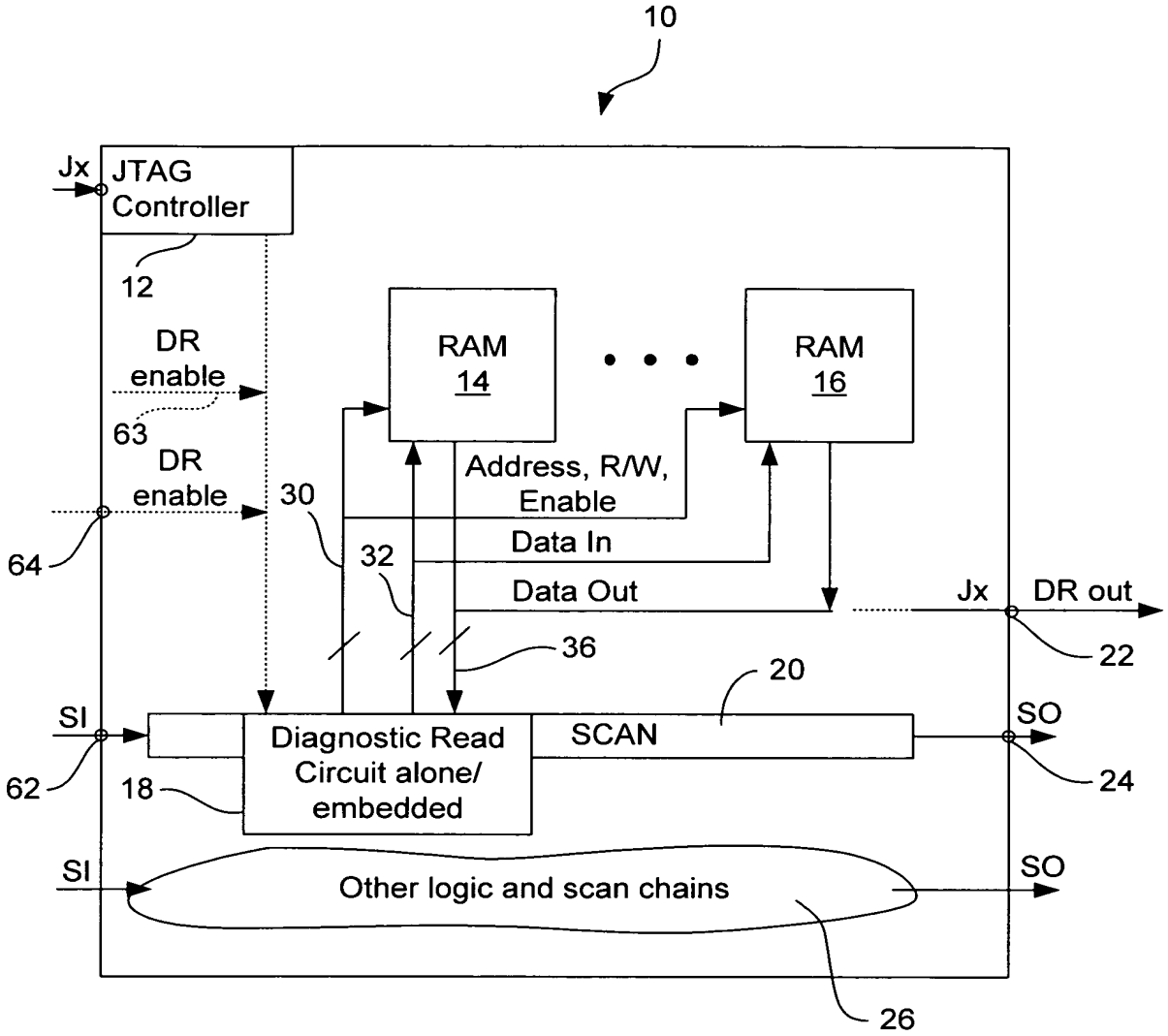

FIG. 1